



5005.1067

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Re: Application of: Franz CEMIC et al.
Serial No.: 10/729,588 **Confirmation No.:** 1541
Filed: 12/05/2003
For: METHOD AND MICROSCOPE FOR DETECTING
IMAGES OF AN OBJECT
Examiner: (not yet known)
Art Unit: 2621

July 30, 2004

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:


In accordance with the provisions of 37 C.F.R. § 1.97, Applicants hereby make of record the documents listed on the accompanying Form PTO-1449 (1 page) for consideration by the Examiner in connection with the examination of the above-identified patent application. Some of the documents were cited in a European Search Report, a copy of which is submitted herewith together with copies of the foreign patent documents listed. Some or all of the references may not constitute prior art under U.S. patent laws.

If any additional fees are deemed to be due at this time, the Assistant Commissioner is authorized to charge payment of the same to Deposit Account No. 50-0552.

5005.1067

It is respectfully requested that the references cited in the accompanying PTO-1449 form be considered and made of record. It is respectfully submitted that the pending claims are patentable over all of the references made of record at this time.

Respectfully Submitted,
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FORM PTO-1449
(REV. 7-80)

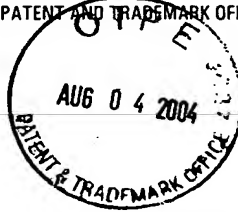
U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.: 5005.1067

SERIAL NO.: 10/729,588

LIST OF PRIOR ART CITED BY APPLICANT

(Use several sheets if necessary)



APPLICANT(S): Franz CEMIC et al.

FILING DATE: 12/05/2003

GROUP: 2621

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
	AA	3	8	1	4	5	2	1	June 4, 1974	Free	356	156	
	AK	9	9	2	3	9	5	9	Nov. 27, 2001	Blaesing-Bangert et al.	356	614	
	AG	20	02	00	57	8	3	9	May 16, 2003	Rinn et al.	382	199	
	AD												
	AE												
	AE												
	AG												
	AH												
	AI												

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
													YES	NO
	AJ	9	9	9	7	9	4	92	Nov. 11, 1999	DE-Germany			corresponds to U.S. 6,323,953	
	AK	1	0	0	4	7	2	11	May 8, 2002	DE-Germany			corresponds to U.S. 2002/0057839	
	AL													
	AM													
	AN													

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AH	I.S. GRADSHTEYN and I.M. RYZHIK, "Table of Integrals, Series, and Products", pp. 982-983, Academic Press, New York, 1980
	AP	Nicholas DOE, Richard EANDI, "Optical Proximity Effects in Sub-micron Photomask CD Metrology", pp. 1-16, Advanced Imaging Systems, Zygo Corporation, Sunnyvale, CA 94404, Nov. 99
	AR	Joseph W. GOODMAN, "Frequency Analysis of Optical Imaging Systems", Introduction to Fourier Optics, pp. 101-121, McGraw-Hill, San Francisco, 1963
	AS	
	AT	

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.